

SLOVENSKI STANDARD SIST EN IEC 60172:2021

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Nadomešča: SIST EN 60172:2015



Méthode d'essai pour la détermination de l'indice de température des fils de bobinage émaillés et enveloppés de ruban (IEC 60172:2020)1406ef53-14e6-45cb-a844-18a161315300/sist-en-iec-60172-2021

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EUROPEAN STANDARD NORME EUROPÉENNE **EUROPÄISCHE NORM**

EN IEC 60172

January 2021

ICS 29.060.10

Supersedes EN 60172:2015 and all of its amendments and corrigenda (if any)

English Version

Test procedure for the determination of the temperature index of enamelled and tape wrapped winding wires (IEC 60172:2020)

Méthode d'essai pour la détermination de l'indice de température des fils de bobinage émaillés et enveloppés de ruban (IEC 60172:2020)

Prüfverfahren zur Bestimmung des Temperaturindex von Lackdrähten und bandumwickelten Drähten (IEC 60172:2020)

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https://standards.iteh.ai/catalog/standards/sist/1406ef53-14e6-45cb-a844-

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CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

European foreword

The text of document 55/1876/FDIS, future edition 5 of IEC 60172, prepared by IEC/TC 55 "Winding wires" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 60172:2021.

The following dates are fixed:

- latest date by which the document has to be implemented at national (dop) 2021-09-28 level by publication of an identical national standard or by endorsement
- latest date by which the national standards conflicting with the (dow) 2023-12-28 document have to be withdrawn

This document supersedes EN 60172:2015 and all of its amendments and corrigenda (if any).

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Endorsement notice

iTeh STANDARD PREVIEW

The text of the International Standard IEC 60172:2020 was approved by CENELEC as a European Standard without any modification. (standards.iteh.ai)

In the official version, for Bibliography <u>Herofollowing</u>, <u>notes</u> have to be added for the standards indicated: https://standards.iteh.ai/catalog/standards/sist/1406ef53-14e6-45cb-a844-

IEC 60317 (series)		1315300/sist-en-iec-60172-2021 Harmonized as EN 60317 (series)
IEC 60455-3-5	NOTE	Harmonized as EN 60455-3-5
IEC 60464-3-2	NOTE	Harmonized as EN 60464-3-2

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: <u>www.cenelec.eu</u>.

Publication	<u>Year</u>	Title	<u>EN/HD</u>	<u>Year</u>
IEC 60216-1	-	Electrical insulating materials - Thermal endurance properties - Part 1: Ageing procedures and evaluation of test results	EN 60216-1	-
IEC 60216-3		Electrical insulating materials - Thermal endurance properties - Part 3: Instructions for calculating thermal endurance characteristics <u>SIST EN IEC 60172:2021</u> standards.iteh.ai/catalog/standards/sist/1406ef53-14e6-45 18a161315300/sist-en-iec-60172-2021		-



iTeh STANDARD PREVIEW (standards.iteh.ai)



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INTERNATIONAL STANDARD

NORME INTERNATIONALE



Test procedure for the determination of the temperature index of enamelled and tape wrapped winding wirestandards.iteh.ai)

Méthode d'essai pour la détermination de l'<u>indir</u>e de température des fils de bobinage émaillés et enveloppés de rubanist/1406ef53-14e6-45cb-a844-18a161315300/sist-en-iec-60172-2021

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

TEST PROCEDURE FOR THE DETERMINATION OF THE TEMPERATURE INDEX OF ENAMELLED AND TAPE WRAPPED WINDING WIRES

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International Standard IEC 60172 has been prepared by IEC Technical Committee 55: Winding wires.

This fifth edition cancels and replaces the fourth edition published in 2015. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- revision of 3.1, definition of thermal index;
- revision of 3.3, time to failure;
- revisions to 5.1.1 for clarity and to reduce the range wire size range to which the test applies;
- revisions to 5.1.2 for tape wrapped round and enamelled or tape wrapped rectangular wire for clarity;
- revision to Clause 9 to add the correlation coefficient, r to the report.

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The text of this International Standard is based on the following documents:

FDIS	Report on voting
55/1876/FDIS	55/1893/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "http://webstore.iec.ch" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

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TEST PROCEDURE FOR THE DETERMINATION OF THE TEMPERATURE INDEX OF ENAMELLED AND TAPE WRAPPED WINDING WIRES

1 Scope

This International Standard specifies, in accordance with the provisions of IEC 60216-1, a method for evaluating the temperature index of enamelled wire, varnished or unvarnished with an impregnating agent, and of tape wrapped round and rectangular wire, in air at atmospheric pressure by periodically monitoring changes in response to AC proof voltage tests. This procedure does not apply to fibre-insulated wire or wire covered with tapes containing inorganic fibres.

NOTE The data obtained according to this test procedure provide the designer and development engineer with information for the selection of winding wire for further evaluation of insulation systems and equipment tests.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies to STANDARD PREVIEW

IEC 60216-1, Electrical insulating materials - Thermal endurance properties – Part 1: Ageing procedures and evaluation of test results

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IEC 60216-3, *Electrical*_{st}insulating_{al} materials_{lands}/Thermal-sendurance_a properties – Part 3: Instructions for calculating thermal endurance characteristics

3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at http://www.electropedia.org/
- ISO Online browsing platform: available at http://www.iso.org/obp

3.1 temperature index

TI number which permits comparison of the temperature/time characteristics of an electrical insulating material, or a simple combination of materials, based on the temperature in degrees Celsius which is obtained by extrapolating the Arrhenius plot of life versus temperature to a lifetime of 20 000 h

Note 1 to entry: In case of insulation systems, the temperature index may be derived from known service experience or from a known comparative functional evaluation of an evaluated and established reference insulation system as basis.

[SOURCE: IEC 60050-212:2010, 212-12-11] modified by merging Note 1 into the definition, and to specify a lifetime of 20 000 h.]